

# POLITECNICO MILANO 1863

# First HiPIMS activities at Politecnico di Milano

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# **Innovative techniques of particle acceleration**

Laser driven ion acceleration (TNSA): a non conventional technique to accelerate ions



Near-critical layer

# **Deposition of novel targets by HiPIMS**

**Ultralow dense layer** 

• Density 10 mg/cm<sup>3</sup>

Ultra porous C foam

• Deposited by PLD

Laser Pulse

Solid free standing layer

- Usually a thin metallic foil (e.g. Al, Ti, etc.)
- Layer thickness (10ns of nm up to 10 μm) influences max. energy of ions
- Roughness affects experiment reproducibility
- Possible presence of holes
- Need of carefull positioning



M. Passoni et al. *Phys Rev Acc Beams* **19.6** (2016) A. Macchi et al., Rev. Mod. Phys., 85 751 (2013)

# HiPIMS apparatus @ POLIMI





**Role of process parameters and deposition schemes** 

As a first attempt deposition of stainless steel investigating the role of process parameters

## **Apparatus Features**

• Two 3 inch cathodes in sputter up configuration

• Near-critical layer (density of few

• More and hotter relativistic electrons

mg/cm<sup>3</sup>) micrometer thick

• More ions at higher energy

- Two generators with positive and negative polarity output
- Four inch anode as substrate holder

**Enhanced TNSA** 

- Substrate heater up to 400° C
- Three process gas lines
- Four channel oscilloscope for monitoring of pulse current
- 1200 l/s TMP reach high and fast vacuum conditions

Pulse genetator features	Channel A 6 kV	Channel B 1.5 kV
Pulse output voltage	+/-1 kV	+/-1 kV
Pulse Time Conditions	UP+; UP-; BP	UP+; UP-; BP
HiPIMS ON time	$T_{on} + / - \ge 20 \ \mu s$	$T_{on} + / - \ge 20 \ \mu s$
HiPIMS OFF time	$T_{off} + / - \ge 20 \ \mu s$	$T_{\rm off} + /- \geq 20 \ \mu s$
HiPIMS freq. conditions	$\sum (T_{on} + T_{off}) \ge 500 \ \mu s$ (2 kHz)	
MF ON and OFF times	$T_{on/off} + / - \ge 5 \ \mu s$	$T_{on/off} + / - \ge 5 \ \mu s$
MF Frequency conditions	$\sum (T_{on} + T_{off}) \ge 20 \ \mu s$ (50 kHz)	











### 1. Two independent unipolar HiPIMS source

2. Unipolar HiPIMS source + Bias (properly synchronized)

### **Deposit target by HiPIMS**

- Wide variety of materials • Different compositions
- Smooth films
- Direct deposition on the holder
- Need of free-standing films on mm sizes

- 3. Bipolar HiPIMS source + Bias (properly synchronized)
- 4. Superimposed Bipolar HiPIMS source + MF

## **Comparison with Pulsed Laser Deposition**

Deposition of compact carbon coatings with two different high energy PVD techniques: HiPIMS and Pulsed Laser Deposition.



# **HiPIMS** (target = Stainless Steel, P<sub>Ar</sub> = 1.3 Pa, **I-V characteristics dcMS** (target = Stainless Steel, P<sub>Ar</sub> = 1.3 Pa, $t_{dep} 40 min$ ) t<sub>dep</sub> 40 min) $\Delta V_{lin} = 620 - 750$ V1 = 550 V V1 = 800 V, V2 = 50 V (bias), $t_{on} = 100 \ \mu s$ , $t_{off} = 2400 \ \mu s$ , $f = 400 \ Hz$ Cur 600 Voltage



V1 = 800 V, V2 = 50 V (bias),

 $t_{on} = 4 \times 25 \ \mu s BIPOLAR$ 

 $t_{off} = 600 \ \mu s$ , f = 1600 Hz

V1 = 800 V, V2 = 50 V (bias),

 $t_{on} = 25 \ \mu s, t_{off} = 600 \ \mu s, f = 1600 \ Hz$ 



V1 = 800 V, V2 = 50 V (bias),

t<sub>off.2</sub> = **2340 μs**, f = **1600 Hz** 

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 $t_{on} = 4 \times 25 \ \mu s$  UNIPOLAR,  $t_{off.1} = 20 \ \mu s$ ,

### V1 = 1000 V, V2 = 200 V (bias), $t_{on} = 4 \times 25 \ \mu s \ UNIPOLAR, t_{off,1} = 20 \ \mu s,$ t<sub>off,2</sub> = **2340 μs**, f = **1600 Hz**





 $\Delta V_{\mu} = 640 - 560$ 

100 ·

• 50-950

800

**---** 100-1900

1000

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 $V1 = 650 \text{ V}, P_{Ar} = 0.9 \text{ Pa}, t_{on} = 25 \text{ } \mu\text{s}, t_{off} = 475$ μs, no bias

### **Preliminar** Analysis

- Film morphology affected both by pulse voltage and bias
- Bipolar mode seems to have little effect compared with unipolar one
- Check of the I-V characteristics is a possible route to determine the different deposition regimes

## **Preliminar Analysis**

- Amorphous compact morphology
- Bias greatly influences thickness 30 nm vs 60 nm
- Similar morphology compared with Pulsed Laser Deposition
- From Raman analysis Carbon deposited at higher energy with PLD

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